





# **FQA90N08**

## **80V N-Channel MOSFET**

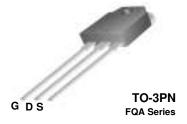
#### **General Description**

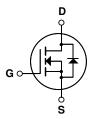
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand a high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as automotive, high efficiency switching for DC/DC converters, and DC motor control.

#### **Features**

- 90A, 80V,  $R_{DS(on)}$  = 0.016 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 84 nC)
- Low Crss (typical 200 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating





# **Absolute Maximum Ratings** T<sub>C</sub> = 25 °C unless otherwise noted

Symbol	Parameter		FQA90N08	Units	
V <sub>DSS</sub>	Drain-Source Voltage		80	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25	℃)	90	Α	
	- Continuous (T <sub>C</sub> = 100 °C)		63.5	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	360	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	1360	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	90	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	21.4	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.5	V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25 °C)		214	W	
	- Derate above 25 °C		1.43	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	.€	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	℃	

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.7	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V
$\Delta BV_{DSS}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°	C	0.1		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V			1	μА
		V <sub>DS</sub> = 80 V, T <sub>C</sub> = 150 °C			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics		·			
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 45 A		0.012	0.016	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 45 A (Note of	1)	52		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		2500 900 200	3250 1170 260	pF pF pF
	,			200	200	P,
	Ing Characteristics Turn-On Delay Time			30	70	ns
t <sub>d(on)</sub> t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 40 \text{ V}, I_{D} = 90 \text{ A},$		360	730	ns
	Turn-Off Delay Time	$R_G = 25 \Omega$		100	210	ns
t <sub>d(off)</sub>	Turn-Off Fall Time	(Note 4,		160	330	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 64 V, I <sub>D</sub> = 90 A,		84	110	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{DS} = 64 \text{ V}, I_D = 90 \text{ A},$ $V_{GS} = 10 \text{ V}$		17		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4,	5)	42		nC
gu						
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				90	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F				360	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 90 \text{ A}$			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 90 \text{ A},$		87		ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		265		nC

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.23mH, I<sub>AS</sub> = 90A, V<sub>DD</sub> = 25V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25 ℃ 3. I<sub>SD</sub> ≤ 90A, di/dt ≤ 300A/μs, V<sub>DD</sub> ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25 ℃ 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

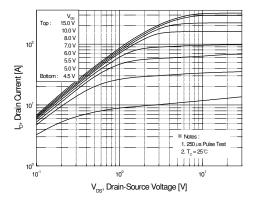


Figure 1. On-Region Characteristics

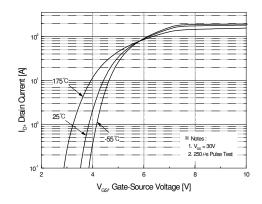


Figure 2. Transfer Characteristics

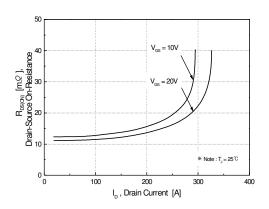


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

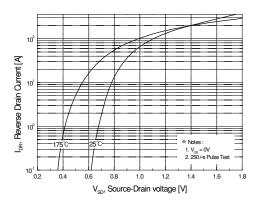


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

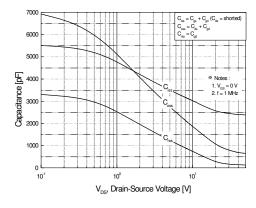


Figure 5. Capacitance Characteristics

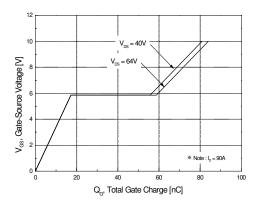
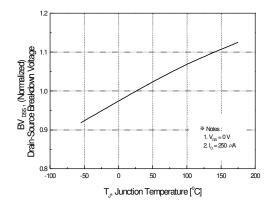


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)



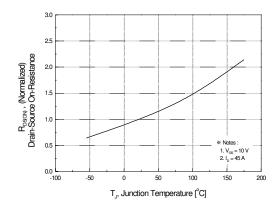
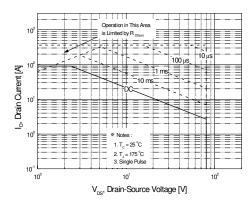


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



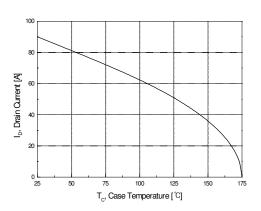


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

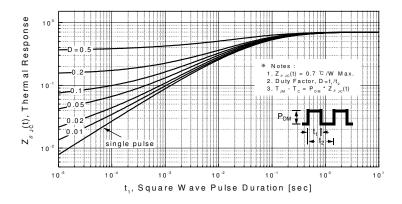
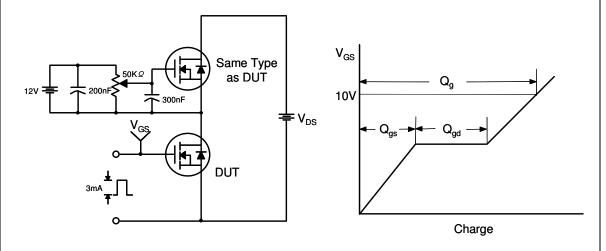


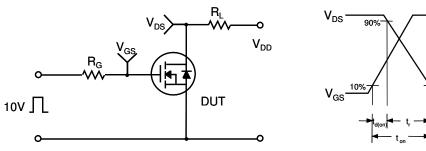
Figure 11. Transient Thermal Response Curve

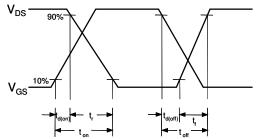
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## **Gate Charge Test Circuit & Waveform**

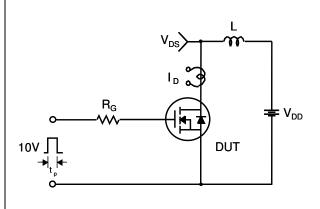


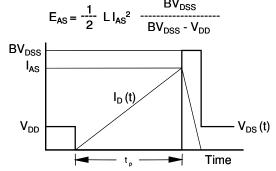
## **Resistive Switching Test Circuit & Waveforms**



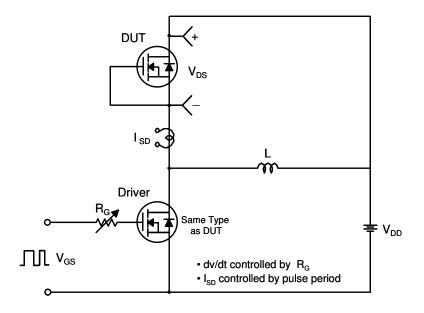


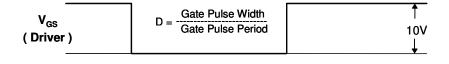
## **Unclamped Inductive Switching Test Circuit & Waveforms**

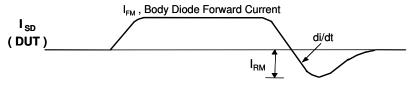




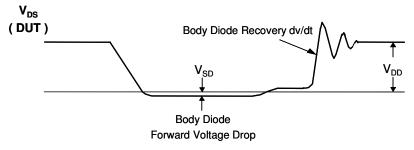
## Peak Diode Recovery dv/dt Test Circuit & Waveforms





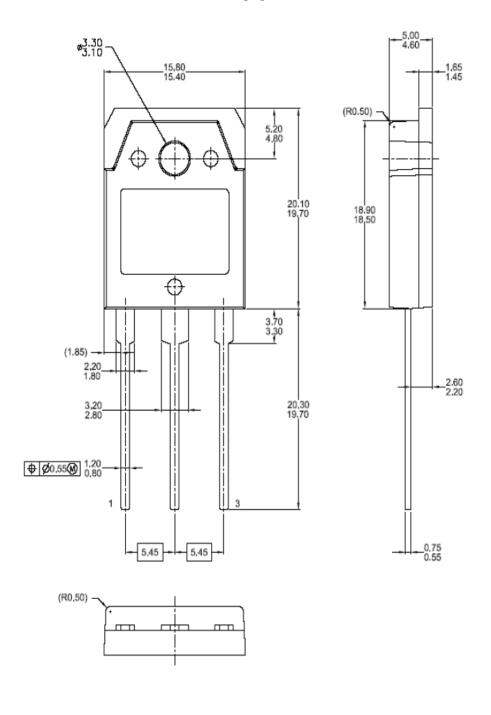


Body Diode Reverse Current



# **Mechanical Dimensions**

# TO-3PN



Dimensions in Millimeters

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